

## Correction to “Initial Phase of Photoelectrochemical Conditioning of Silicon in Alkaline Media: Surface Chemistry and Topography”

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*J. Phys. Chem. C* **2013**, *117* (32), 16381–16391. DOI: 10.1021/jp401853p

Zhuangqun Huang of the California Institute of Technology has been added to the authors. We include Dr. Huang as an author because of the importance of his contribution regarding the decisive AFM experiments

In section “2. Experimental and Procedures”. Change the first sentence of the third paragraph from “Tapping-mode AFM (TM-AFM) images were recorded in ambient air with a Nanoscope IIIa (Digital Instruments) using Si-tips (NSC15/no Al, with stiffness in the 30–50 N/m range)” to “Tapping-mode AFM (TM-AFM) images were recorded in ambient air. Figure 5 was recorded with a Nanoscope IIIa (Digital Instruments) using Si-tips (NSC15/no Al, with stiffness in the 30–50 N/m range). Figure 16 was recorded with a Bruker Dimension Icon with Scan Asyst, using tips with a radius of 2 nm. The Scan Asyst mode performed a very fast force curve at every pixel in the image, with the peak force of each curve used as the imaging feedback signal.”

Published: January 13, 2014